

Notice of References Cited	Application/Control No. 10/807,129		Applicant(s)/Patent Under Reexamination LIN, WEN-JIAN	
	Examiner Evelyn A. Lester		Art Unit 2873	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,500,761	03-1996	Goossen et al.	359/290
*	B	US-5,739,945	04-1998	Tayebati, Parviz	359/291
*	C	US-5,978,127	11-1999	Berg, John E.	359/291
*	D	US-6,618,187	09-2003	Pilossof, Nissim	359/291
*	E	US-6,747,800	06-2004	Lin, Wen-Jian	359/585
*	F	US-6,760,146	07-2004	Ikeda et al.	359/291
*	G	US-6,859,301	02-2005	Islam et al.	359/291
*	H	US-6,882,461	04-2005	Tsai et al.	359/290
*	I	US-6,912,022	06-2005	Lin et al.	349/105
*	J	US-6,958,847	10-2005	Lin, Wen-Jian	359/291
*	K	US-2004/0209195	10-2004	Lin, Wen-Jian	430/315
*	L	US-2005/0024557	02-2005	Lin, Wen-Jian	349/105
*	M	US-2005/0168849	08-2005	Lin, Wen-Jian	359/850

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.